

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/534,536	FUKUSHIMA ET AL.	
Examiner		Art Unit		Page 1 of 1
HENOK G. HEYI		2627		

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,486,870 A	12-1984	Pettigrew et al.	369/30.04
*	B	US-4,954,065 A	09-1990	Shindo et al.	425/175
*	C	US-5,905,705 A	05-1999	Takeda et al.	360/51
*	D	US-5,933,397 A	08-1999	Yamashita et al.	369/44.28
*	E	US-6,628,576 B1	09-2003	Watanabe et al.	369/30.17
*	F	US-2004/0145086 A1	07-2004	Yusa, Atsushi	264/328.11
*	G	US-2004/0257970 A1	12-2004	Yamaga et al.	369/275.4
*	H	US-6,898,171 B1	05-2005	Sugaya et al.	369/275.3
*	I	US-2005/0199778 A1	09-2005	Kadowaki et al.	250/201.5
*	J	US-2005/0254795 A1	11-2005	Muramatsu et al.	386/125
*	K	US-2006/0098559 A1	05-2006	Hino et al.	369/275.1
*	L	US-7,050,386 B2	05-2006	Ueda, Eiji	369/275.4
*	M	US-7,420,889 B2	09-2008	Ishibashi et al.	369/44.13

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.